Notice of References Cited Application/Control No. O9/975,864 Examiner Art Unit Page 1 of 1 Mary J. Steelman Applicant(s)/Patent Under Reexamination HARRISON ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,269,363 B1	07-2001	Matias, Yossi	707/5
*	В	US-6,772,399 B2	08-2004	Saluja et al.	716/2
*	С	US-6,807,651 B2	10-2004	Saluja et al.	716/2
*	D	US-6,848,099 B2	01-2005	Harrison et al.	717/154
*	Е	US-2003/0167462 A1	09-2003	Harrison et al.	717/154
*	F	US-2003/0018603 A1	01-2003	Tip et al.	707/1
	G	US-			
	Н	US-		•	
	_	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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	0					
	Р					
	ø					
	R					
	S					
	Τ					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	U	Stephenson, Mark; Babb, Jonathan; Amarasinghe, Saman; "Bitwidth Analysis with Application to Silicon Compilation", p. 108-120, ACM 2000, retrieved from ACM 04/28/2005.				
	V					
	w					
	x					

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.